

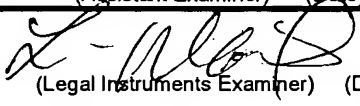


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/088,689	KAWANABE, YOSHITAKA	
	Examiner	Art Unit	
	Eva Yi Zheng	2611	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
375		316			375	134			
INTERNATIONAL CLASSIFICATION					342	371	372	382	
H	0	3	K	9/00	455	182			
				/					
				/					
				/					
				/					

Eva Zheng 10/27/06 (Assistant Examiner) (Date)		 CHIEH M. FAN SUPERVISORY PATENT EXAMINER (Primary Examiner) (Date) 10/30/06	Total Claims Allowed: 4	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1			31			61			91			121			151
	2			32			62			92			122			152
	3			33			63			93			123			153
1	4			34			64			94			124			154
2	5			35			65			95			125			155
	6			36			66			96			126			156
	7			37			67			97			127			157
3	8			38			68			98			128			158
4	9			39			69			99			129			159
	10			40			70			100			130			160
	11			41			71			101			131			161
	12			42			72			102			132			162
	13			43			73			103			133			163
	14			44			74			104			134			164
	15			45			75			105			135			165
	16			46			76			106			136			166
	17			47			77			107			137			167
	18			48			78			108			138			168
	19			49			79			109			139			169
	20			50			80			110			140			170
	21			51			81			111			141			171
	22			52			82			112			142			172
	23			53			83			113			143			173
	24			54			84			114			144			174
	25			55			85			115			145			175
	26			56			86			116			146			176
	27			57			87			117			147			177
	28			58			88			118			148			178
	29			59			89			119			149			179
	30			60			90			120			150			180